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Assistant Commissioner for Patents,
Washington, D.C. 20231 on April 17, 2002

William R. Allen, Ph.D., Reg. No. 48,389

17 April 2002

Date

Applicants:

James Scott Tyler

Serial No:

10/030,723

Filed:

January 11, 2002

Group Art Unit:

Unknown

Examiner: Title: Unknown HIGH SPEED SYMMETRICAL PLASMA TREATMENT

Atty Docket:

NOR-933A

Cincinnati, Ohio 45202

April 17, 2002

Assistant Commissioner for Patents Washington, DC 20231

INFORMATION DISCLOSURE STATEMENT

In accordance with the duty of candor and good faith imposed by 37 C.F.R. §1.56, and means of complying therewith according to 37 C.F.R. §\$1.97 and 1.98, the references listed on the attached Form PTO-1449 are called to the attention of the United States Patent and Trademark Office in connection with the above-identified patent application. Copies of the cited references are enclosed herewith and Applicant requests that the Examiner

consider the cited references and make an independent evaluation of their materiality.

It is submitted that none of the cited references of record or now cited, either alone or in combination, disclose or render obvious the subject matter claimed in the present application.

Applicant does not believe that any fees are due in connection with this response. However, if such petition is due or any fees are necessary, the Commissioner may consider this to be a request for such and charge any necessary fees to deposit account 23-3000.

Respectfully submitted,

WOOD, HERRON & EVANS, L.L.P.

BY William of allen

William R. Allen, Ph.D. Reg. No. 48,389

2700 Carew Tower Cincinnati, OH 45202 (513) 241-2324

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SUBSTITUTE FOR PTO-1449

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WFORMATION DISCLOSURE

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STATEMENT BY APPLICANT

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. NOR/933A

SERIAL NO. 10/030,723

APPLICANT James Scott Tyler

GROUP

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FILING DATE January 11, 2002

U.S. PATENT DOCUMENTS

EXAMINER INITIAL			PA	TEN	IT N	IUM	IBEF	₹	ISSUE DATE	PATENTEE	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	A.A	3	2	9	4	6	7	0	12/27/66	Charschan et al.	204	298	10/7/63
	A.B	3	6	4	1	9	7	3	2/15/72	Shrader	118	49	11/25/70
	A C	4	2	0	8	1	5	9	6/17/80	Uehara et al.	414	225	
	A D	4	2	5	2	5	9	5	2.24.81	Yamamoto et al.	156	345	
	ΑE	4	2	7	8	5	2	8	7,14.81	Kuehnle et al.	204	298	10/9/79
	A.F	4	3	1	8	7	6	7	3/9/82	Hijikata et al.	156	345	
	A G	4	3	3	6	4	3	8	6/22/82	Uehara et al.	219	121PG	9/16/80
	A.H	4	4	0	5	4	3	5	9/20/83	Tateishi et al.	204	298	
	A.I	4	4	1	8	6	3	9	12/6/83	Wills et al.	118	50	5/19/81
	A.J	4	5	5	0	2	4	2	10/1985	Uehara et al.	156	345	
	АК	4	5	5	0	2	3	9	10/29/85	Uehara et al.	219	121PG	9/27/82

FOREIGN PATENTS OR PUBLISHED FOREIGN PATENT APPLICATIONS

	DOCUMENT NUMBER	PUBLICATION DATE	COUNTRY OR PATENT OFFICE	CLASS	SUBCLASS	TRANSLATION (YES/NO)
A.L	DE 3935002	4/1991	Germany			Abstract Only
A.M	2828066	9/1998	Japan			Abstract Only
A.N	59-164696	9/1984	Japan			Abstract Only
A.0	04-123430	4/1992	Japan			Abstract Only
A.P	03-023137	1/1991	Japan			Abstract Only
A.Q	04-311044	11/1992	Japan			Abstract Only

OTHER DOCUMENTS (Including Author, Title, Date, Place of Publication)

A.R	Panasonic Factory Automation Company, <u>Plasma Cleaning Systems</u> , Brochure, 11/2000
A.S	Panasonic Factory Automation Company, Japanese Brochure, 11/2000
A.T	March Instruments, Inc., In-Line Plasma System, Brochure, 8/1995

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EXAMINER: Initial if citation considered, whether or not in conformance. Draw line through citation only if not in conformance and not considered. Include a copy of this form with next communication to applicant.

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	B.A	4	5	7	5	2	9	9	3/1986	Layton			414	222		
	B.B	4 5 8 4 0 4						5	4/1986	Richards	s		156	345		
	B.C	4 6 3 7 8 5						3	1/20/87	Bumble	et al.		156	345		
	B.D	4	7	0	5	4	4	4	11/1987	Tullis et	al.		118	729X		
	B.E	4	7	7	0	1	2	1	9/13/88	Ebata et	t al.		118	686		2/3/87
	B.F 4 8 1 6 6 3							8	3/28/89	Ukai et a	al.		219	121.43	3	10/20/87
	B.G	6 4 8 1 6 1 1							3/1989	Davis			156	643		
	В.Н	4 8 4 0 7 0 2					0	2	6/20/89	Schumacher, III			156	643		12/29/87
	B.I	4	8	8	9	6	0	9	12/26/89	Canella			204	298		
	B.J	5	0	3	0	0	5	6	7/9/91	Kitayam	ıa et al.		414	749		7/23/90
	B.K	5	0	4	4	8	7	1	9/1991	Davis et al.			414	786		
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	B.S	Ma	teria	als F	₹ese	earc	h C	orpor	ation, <u>1.12 ln</u>	iline produ	uction magnet	ron sput	tering, Journ	nal Article	e, 3 pag	jes
	В.Т	Plas	sma	beh	and	llung	g als	s umv	k, Fraunhofer- <u>weltfreundlich</u> Article, 6 page	ne Alternat						Berlin, D-88348 Saulgau
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	C.A	5	0	7	9	0	3	1	1/1992	Yamazaki et al.		118	729X		
	C.B 5 0 8 6 7 2 9 2/11									Katagiri		118	729		6/13/89
	C.C 5 1 1 6 6 4 0 5/1992 N											118	719X		
	5	2	1	6	2	2	3	6/1/93	Straemke		219	121.43		2/25/91	
	C.E	5	2	5	9	9	4	2	11/1993	Kempf		204	298.25		
	C.F	5	2	8	6	2	9	6	2/1994	Sato		118	719		
	C.G	5	2	8	8	6	8	4	2/1994	Yamazaki et al.		118	723 E X		
	С.Н	5	2	9	2	3	9	3	3/1994	3/1994 Maydan			345		
	C.I	5	3	3 0 2 0 7 7 4/1994 Sato								414	609		
	C.J	5	3	0	3	6	7	1	4/19/94	Kondo et al.		118	719		
	C.K	5	3	1	0	4	1	0	5/1994	Begin		29	25.01		
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INITIAL	D.A	5	3	1	4	2	9	8	5/1994	Kim		414	797.9		
	D.B	5	3	4	5	0	5	6	9/6/94	Frei et al.		219	121.59	9	12/12/91
	D.C	5 3 8 7 2 6 5							2/1995	Kakizaki et al.		118	730X		
	D.D	5	4	3	3	3	7	1	7/18/95	Morisako		228	180.5		10/13/93
	D.E	5	4	8	0	0	5	2	1/2/96	Furr et al.		216	71		10/22/93
	D.F	5	4	9	2	2	6	5	2/20/96	2/20/96 Wandke			205		12/20/94
	D.G	5 5 1 5 9 8						6	5/1996	Turlot et al.		156	345X		
	D.H	5	5	4	2	5	5	9	8/6/96	Kawakami et al.		216	67		2/14/94
	D.1	5	5	7	3	5	9	7	11/12/96	Lantsman		118	723M	Р	
	D.J	5	5	7	6	6	2	9	11/19/96	Turner et al.		324	709		10/24/94
	D.K	5	5	8	7	2	0	5	12/24/96	Saito et al.		427	553	<u></u>	
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	E.A	5	6	0	9	2	9	0	3/11/97	Bobbio et al.		228	206		4/20/95
	E.B	5	6	3	4	7	6	5	6/3/97	Miyoshi		414	786		6/7/95
	E.C	5	6	4	7	9	4	2	7/1997	Haji	· -	156	281		
	E.D	5	7	0	7	4	8	5	1/13/98	Rolfson et al.		156	643.1		12/20/95
	E.E 5 7 6 7 0 0 8 6/1998 Haji											438	612		
	E.F 5 7 7 9 8 0 7 7/1998 Dornfe											134	1.2		
	E.G 5 8 2 3 4 1 6 10/20/98 Haji											228	4.5		7/9/96
	E.H 5 9 5 8 5 1 0 9/1991 Sivara											427	255.6		
	E.I 5 9 7 2 1 6 3 10/26/99 Haji										Haji		345		2/6/98
	E.J	6	0	9	3	9	0	4	7/25/00	Haji		219	121.45	5	7/15/98
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